

**First-Principles Prediction of β -phase SnA_2N_4 (A = Si; Ge) Monolayers:
Outstanding Mechanical Anisotropy and High Electron Mobility for FET
Devices**

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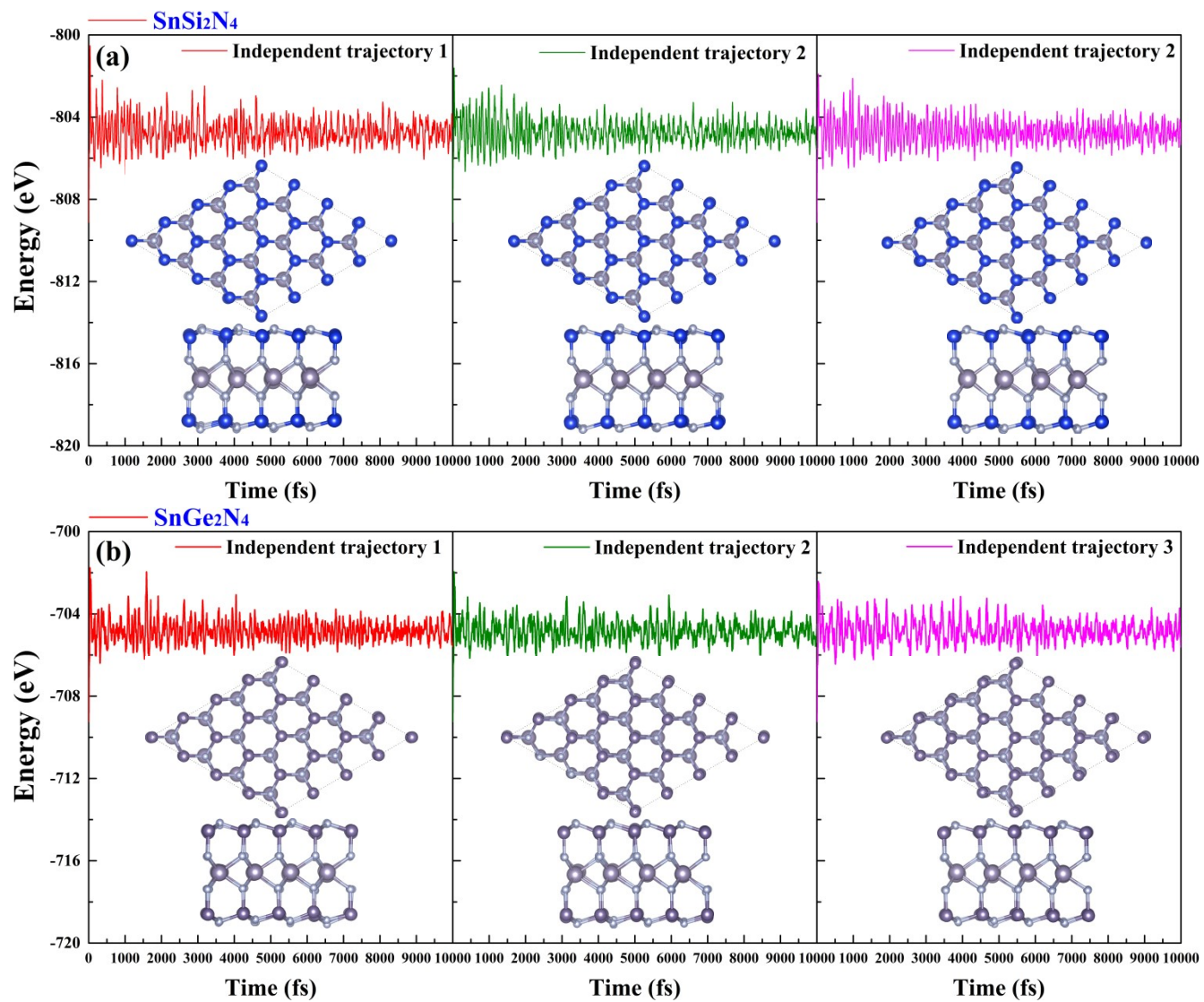


Fig. S1. Calculated AIMD simulations of (a) β -SnSi₂N₄ and (b) β -SnGe₂N₄ monolayers from three independent trajectories (10 ps, 300 K).

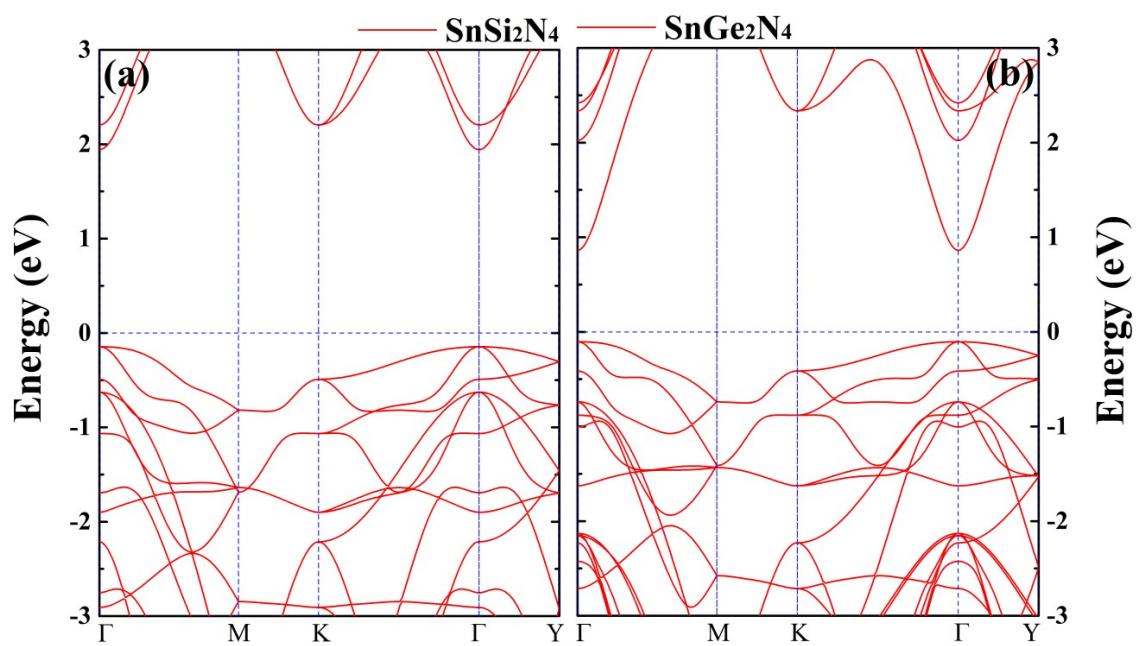


Fig. S2. Calculated band structure of orthogonal β -SnSi₂N₄ (a) and β -SnGe₂N₄ (b) monolayers

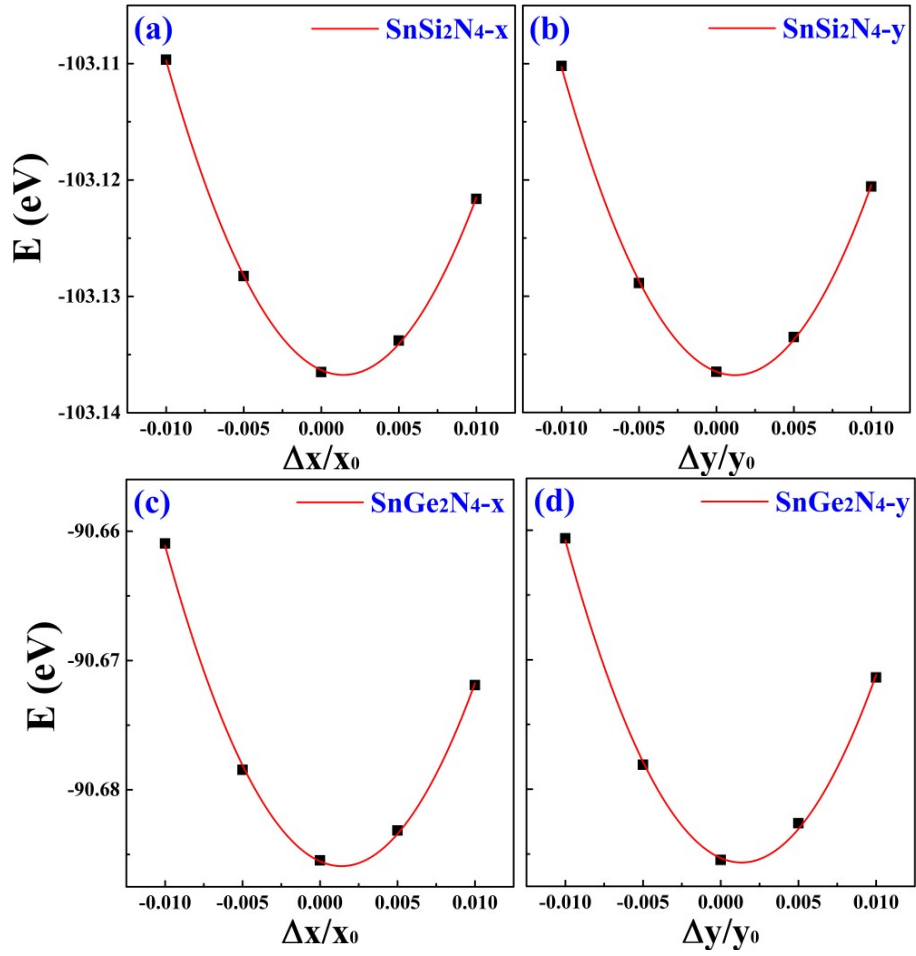


Fig. S3. Total energy of β - SnSi_2N_4 and β - SnGe_2N_4 monolayers as a function of uniaxial strain along the x and y directions, respectively. The in-plane stiffness C can be obtained after fitting the parabola.

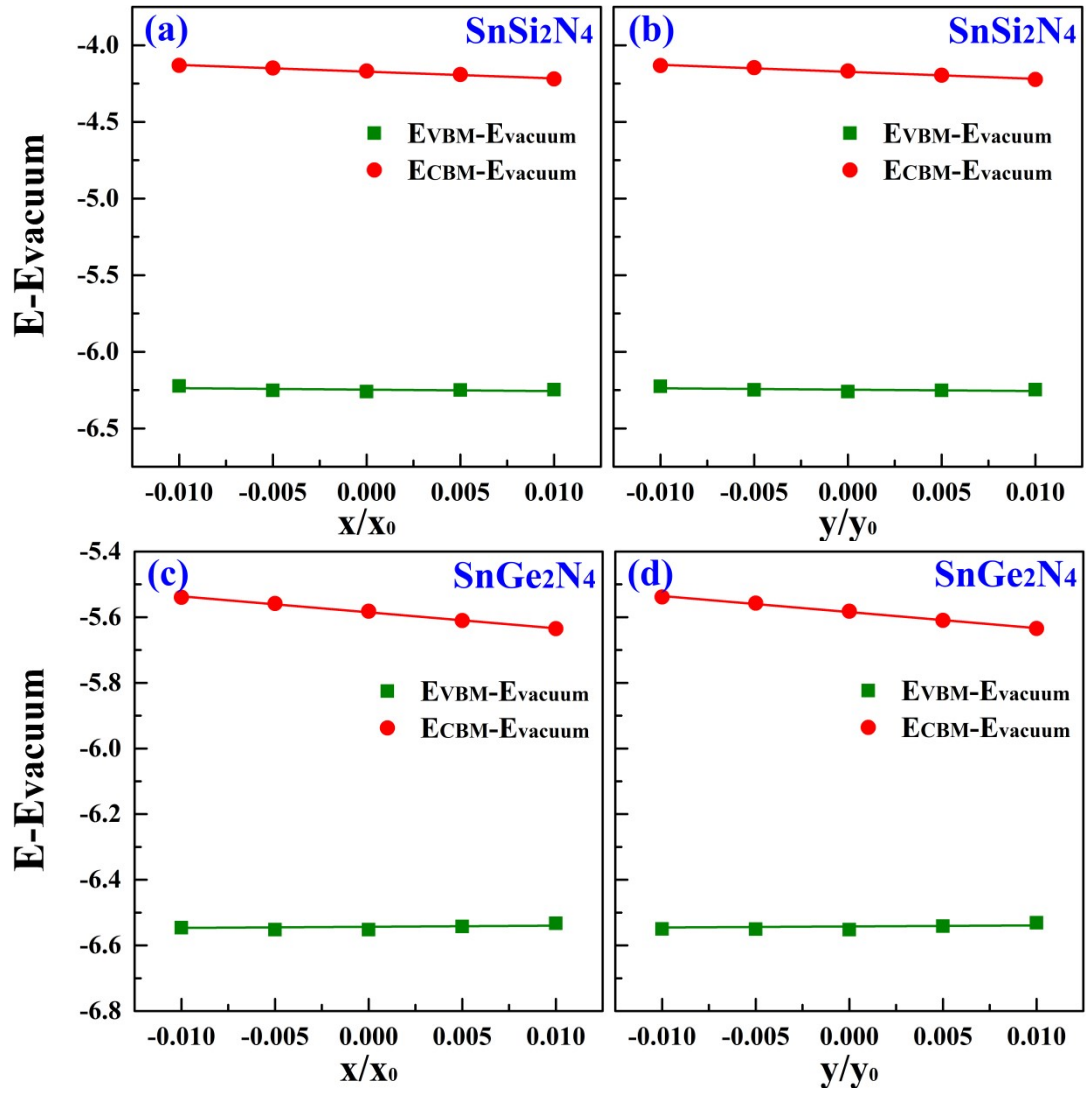


Fig. S4. Band edge positions (CBM and VBM) of β -SnSi₂N₄ and β -SnGe₂N₄ monolayers, referenced to the vacuum level, as a function of lattice strain along the x (a,c) and y (b,d) directions. The slopes of the linear fits to CBM (red circles) and VBM (green squares) correspond to the deformation potential constants for electrons and holes, respectively.